

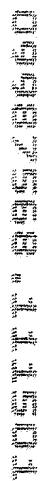
[illegible]

FIG. 1 is a perspective view of a system for measuring the thickness of a substrate. The system includes a substrate 1, a measurement head 2, a base 4, and various components labeled 1 through 28. A coordinate system (X, Y, Z) is shown at the bottom right.

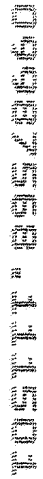
[illegible]

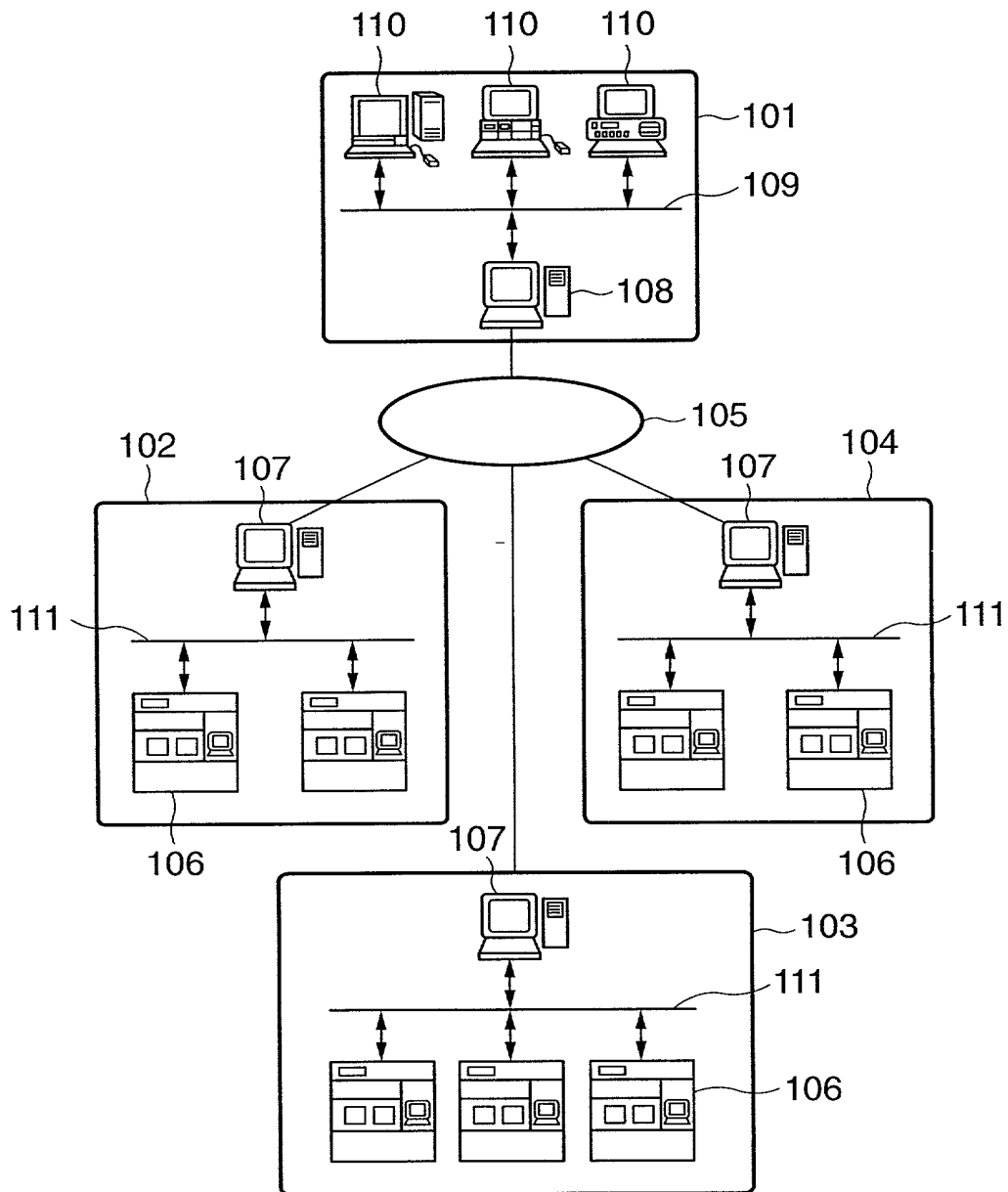
FIG. 4

FIG. 5

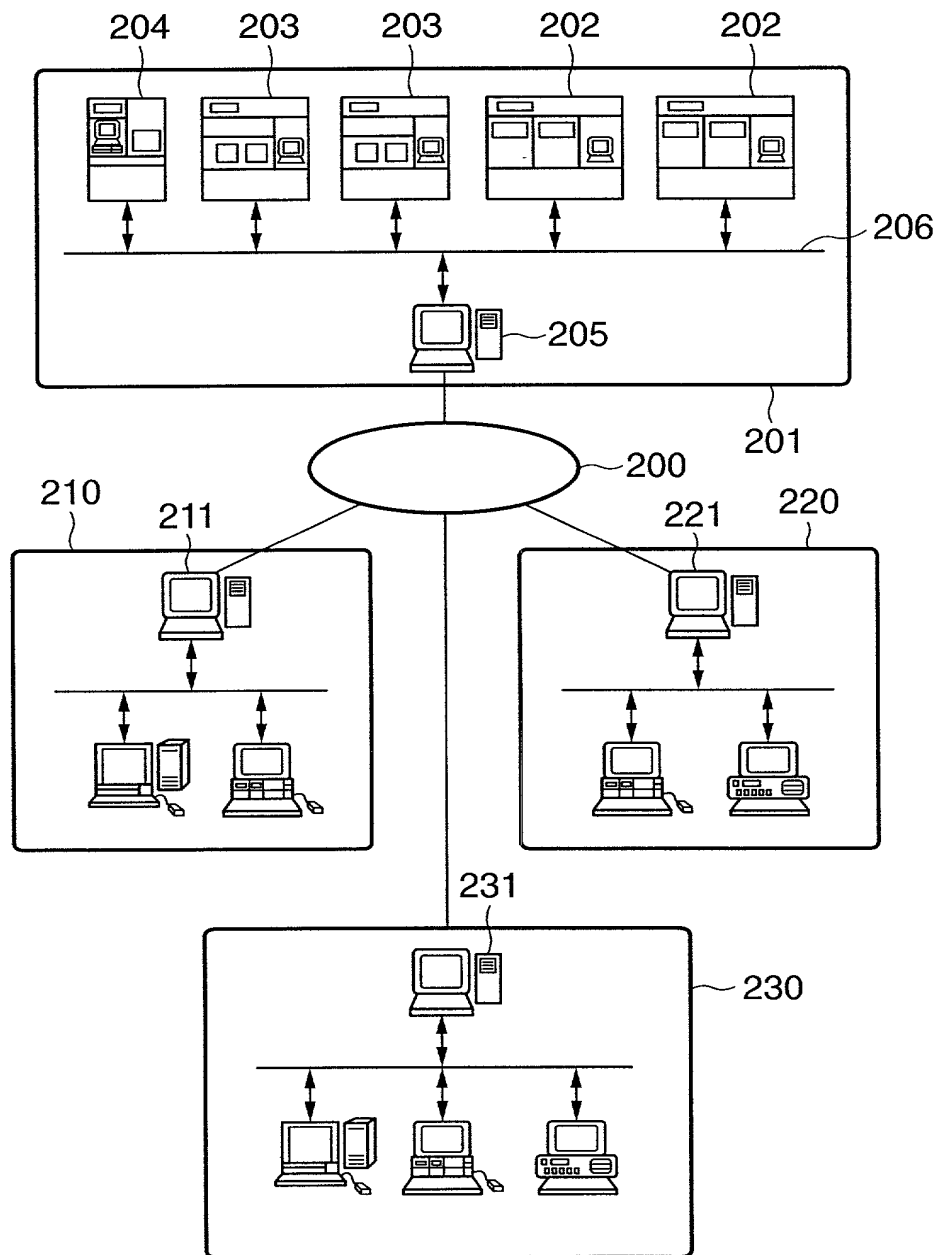


FIG. 6

URL

TROUBLE DB INPUT WINDOW

OCCURRENCE DATE ~ 404

TYPE OF APPARATUS ~ 401

SUBJECT ~ 403

DEVICE S/N ~ 402

DEGREE OF URGENCY ~ 405

SYMPTOM ~ 406

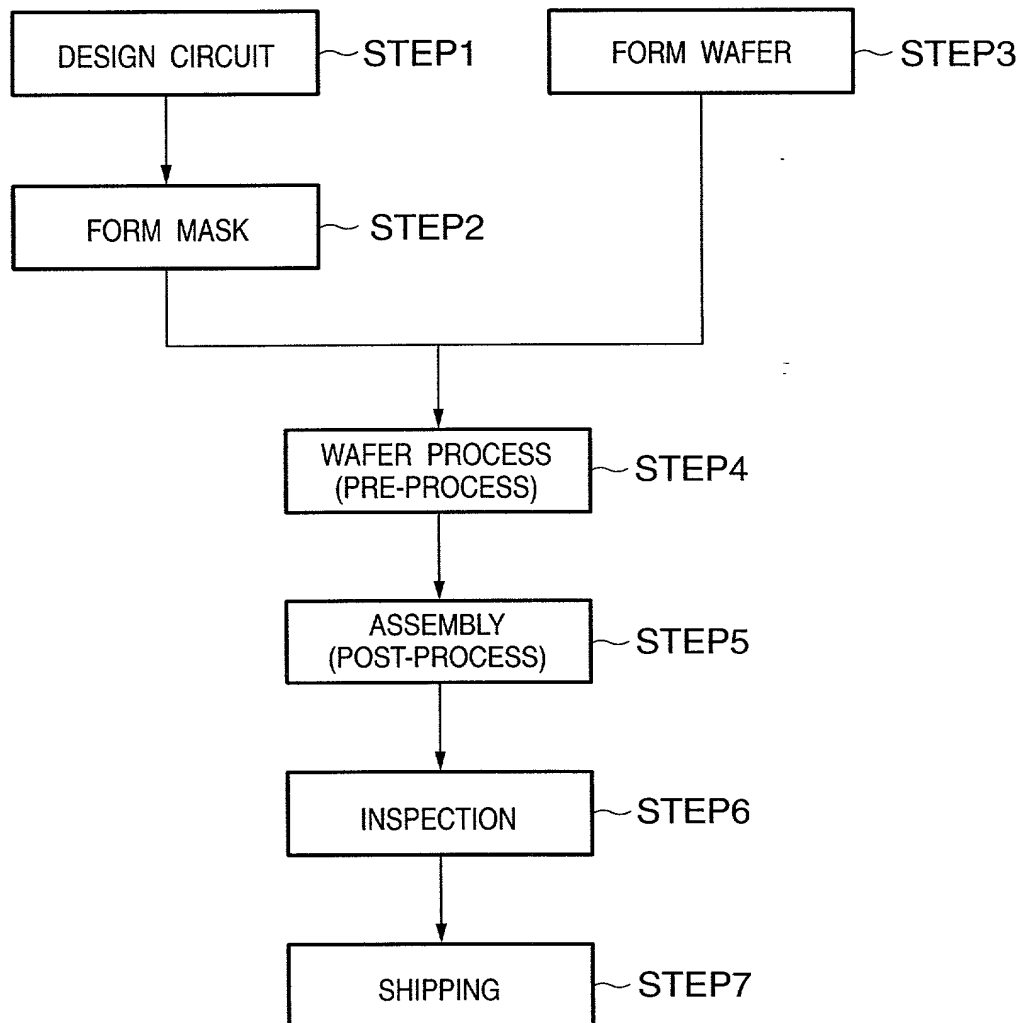
REMEDY ~ 407

PROGRESS ~ 408

410

411

412

FIG. 7

SEMICONDUCTOR DEVICE MANUFACTURING FLOW

FIG. 8

